

Electronic Supplementary Information

Synthesis of 3C/2H/6H heterojunction SiC nanowires with high-performance supercapacitors by thermal evaporation †

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Fig. S1-S9

Table. S1

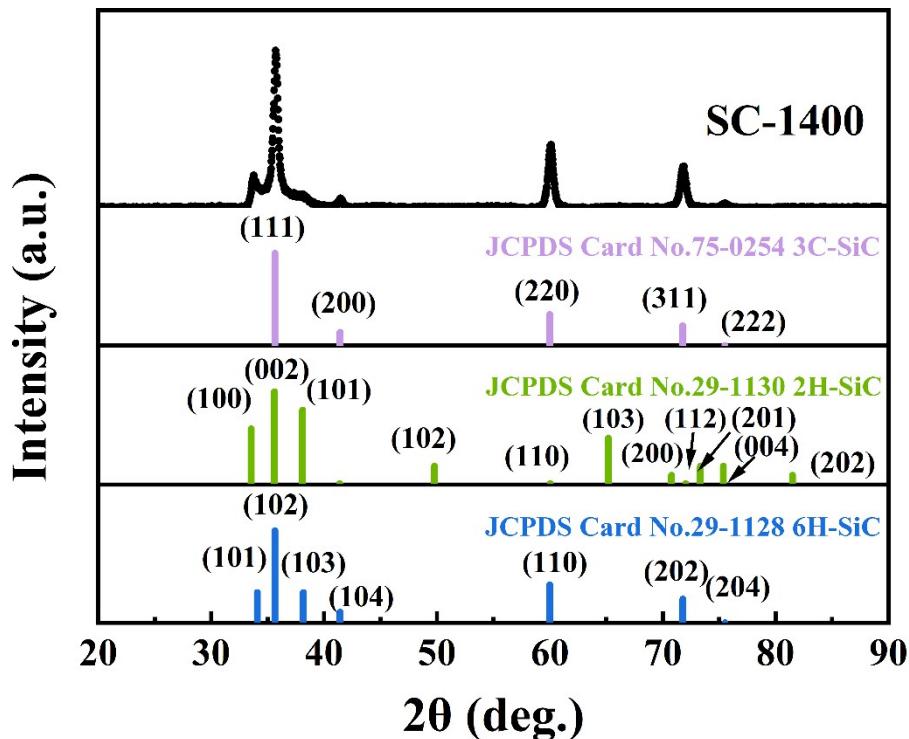


Fig. S1. XRD patterns of SC-1400.

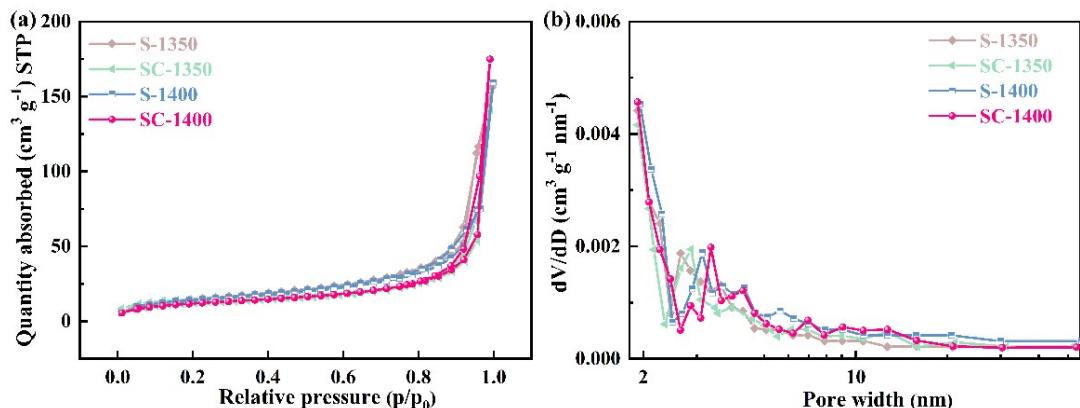


Fig. S2. (a) N_2 adsorption-desorption isotherms and (b) pore size distributions of S-1350, SC-1350, S-1400, and SC-1400.

Table S1. Surface structure of S-1300, SC-1300, S-1400, and SC-1400.

Sample	S-1350	SC-1350	S-1400	SC-1400
SSA ($m^{-2} g^{-1}$)	58.21	57.34	54.08	53.61
Total pore volume ($cm^3 g^{-1}$)	0.061	0.064	0.069	0.071
Average pore width (nm)	2.58	2.87	3.15	3.34

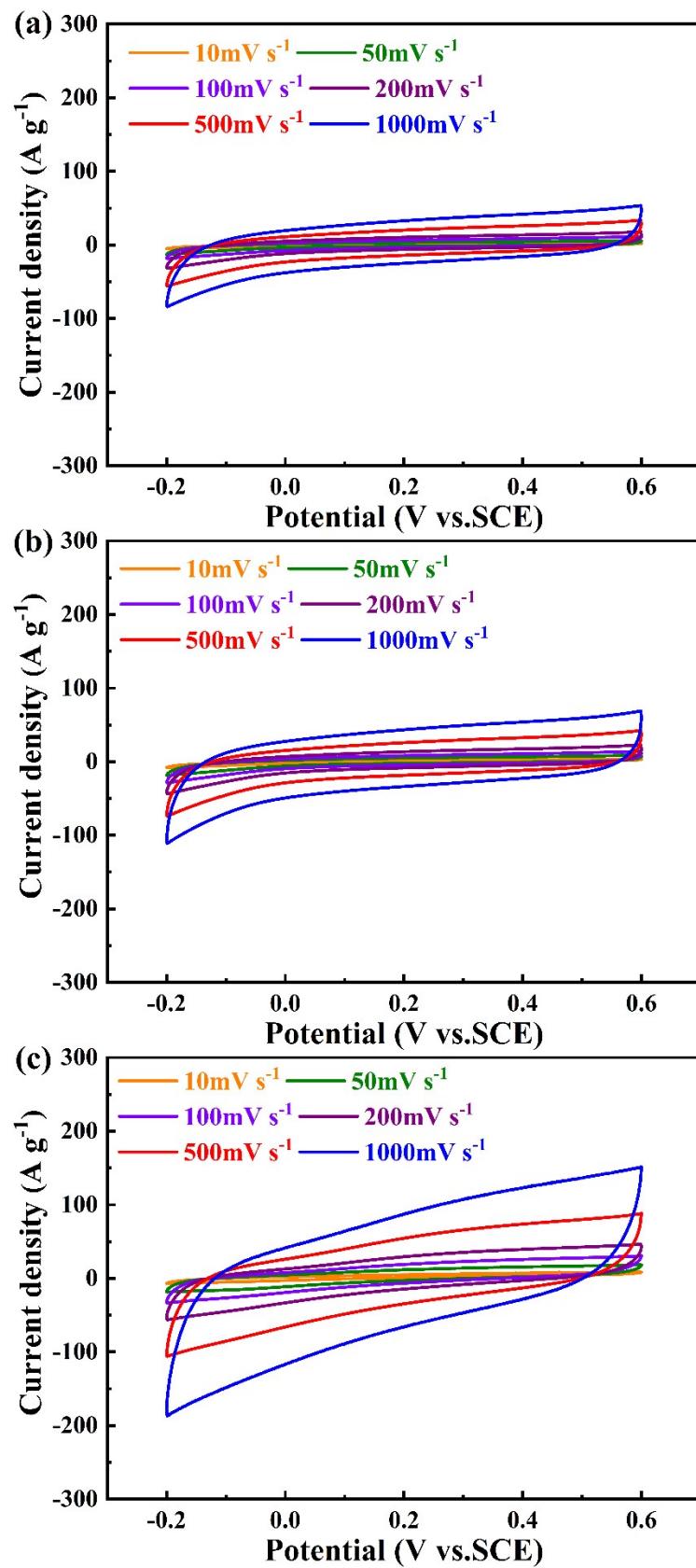


Fig. S3. CV curves of (a) sample S-1350, (b) sample SC-1350, and (c) sample S-1400 at various scan rates ($10\text{-}1000 \text{mV s}^{-1}$).

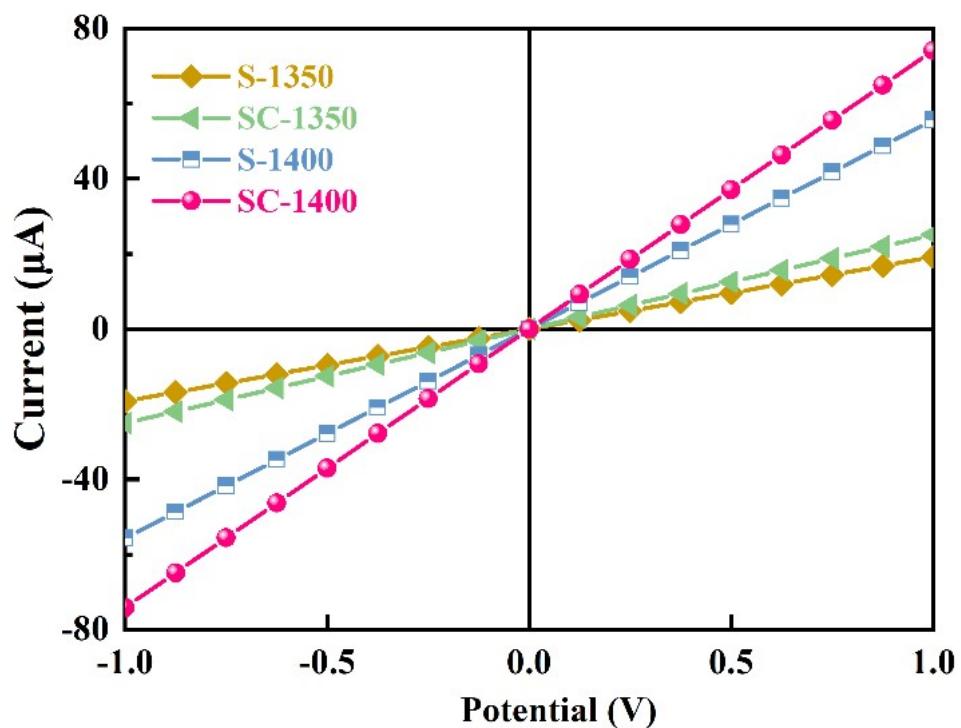


Fig. S4. Conductivity characterization of the SiC NWs.

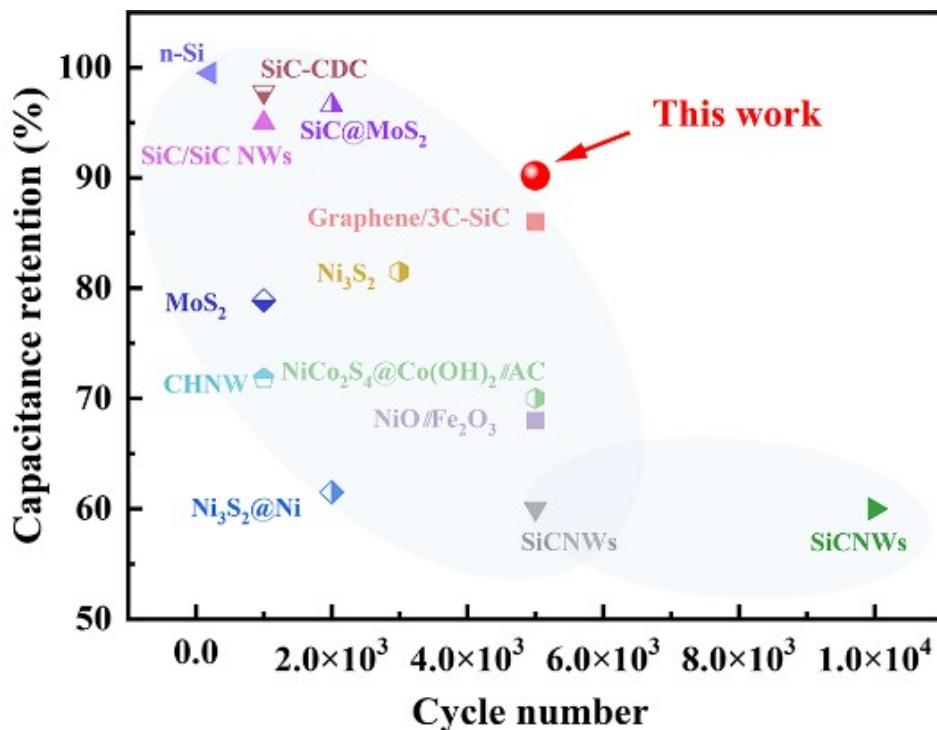


Fig. S5. Comparison of the cyclic stability of SiC NWs in this work with those in the literature. ($\nabla^1 \blacktriangledown^2 \triangle^3 \blacksquare^4 \blacktriangle^5 \blacktriangleright^6 \blackleftarrow^7 \blacksquare^8 \triangleleft^9 \blacktriangleright^{\text{This work}} \blacktriangleright^{\text{SiCNWs}}$)

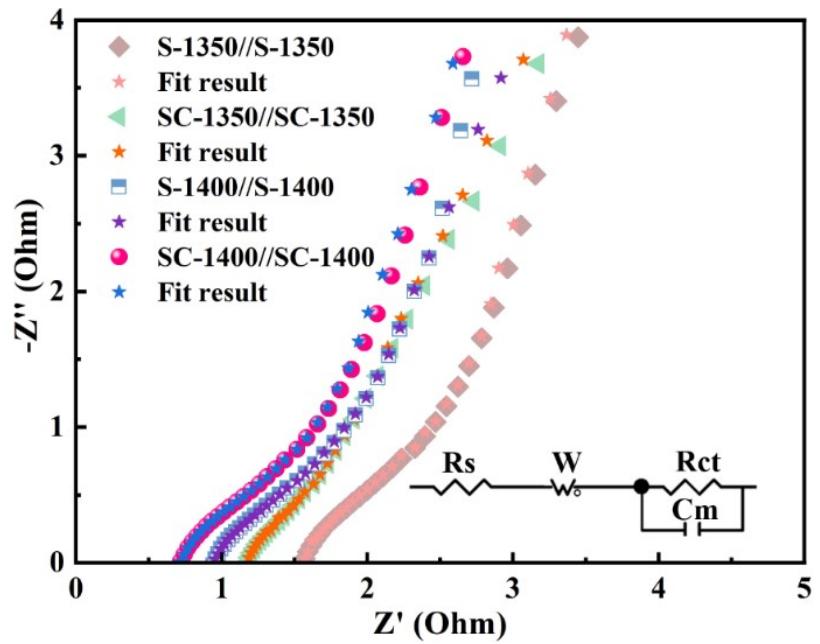


Fig. S6. Nyquist plots of SCs based on S-1350, SC-1350, S-1400, and SC-1400 electrodes.

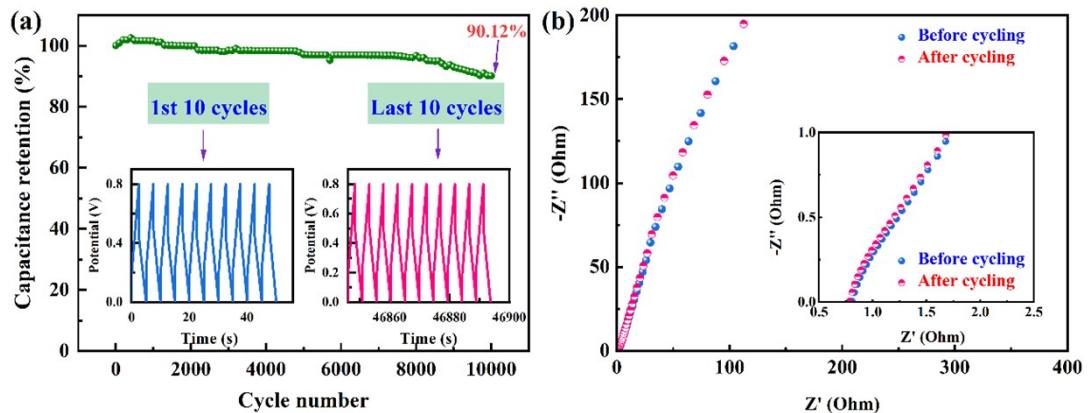


Fig. S7. (a) Cycling performance of SCs based on SC-1400 electrodes at 20 A g⁻¹ for 10,000 cycles; (b) the Nyquist curves of before and after cycling.

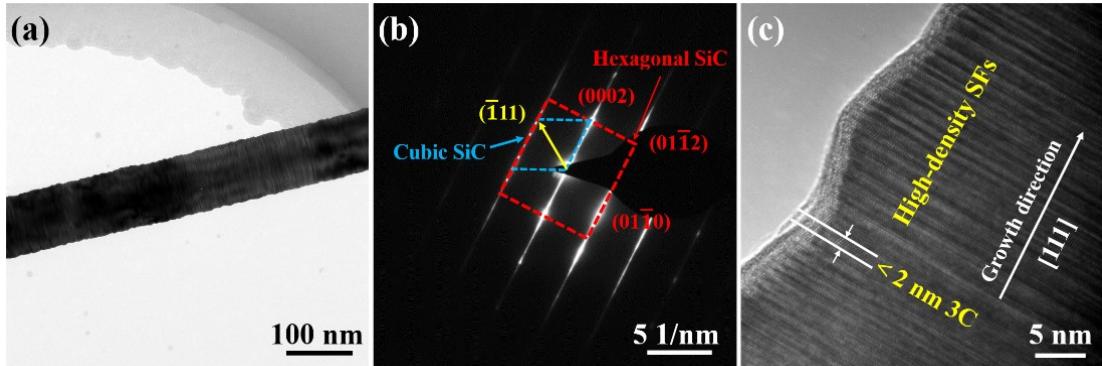


Fig. S8. TEM and HRTEM images of Sample S-1400 after 10,000 cycles. (a) TEM image, (b) SAED patterns, and (c) HRTEM image. Compared to the pre-cycle sample, the diameter of SiC NWs remains unchanged after 10,000 cycles (~90 nm, Fig. S8a†). SAED patterns show severe streaking along the growth direction (Fig. S8b†), indicating a high density of SFs in the SiC NWs. Perfect SiC crystals with crystal domain width greater than 2 nm could not be observed (Fig. S8c†). The lattice and interfacial structures of the SiC NWs remained unchanged, suggesting an excellent cycling stability of the sample.

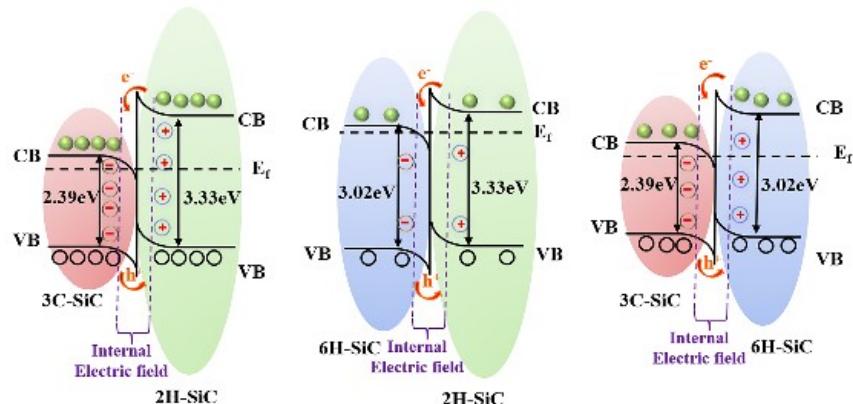


Fig. S9. Band diagrams of electric field for 3C/2H, 6H/2H and 3C/6H heterogeneous structures.

Notes and references

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